

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10511456	PAYNE, PATRICK
	<b>Examiner</b>	<b>Art Unit</b>
	Kim, Edward J	2155

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
709	201-253		Edward J Kim
379	200-207		Edward J Kim
455	1-575.9		Edward J Kim

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
Also searched the Derwent, JPO, EPO, and IBM databases		Edward J Kim
Also conducted inventor search on Patrick Payne		Edward J Kim
Updated East Search	10/18/2007	EJK
Discussed with SPE	10/18/2007	EJK

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>